

<i>Search Notes</i>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10564745	TAKAYAMA ET AL.
Examiner	Art Unit	
	MICHAEL SZPERKA	1644

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
inventor search in eDAN: Takayama, Hiroshi; Shirakawa, Kamon; Yamakawa, Toru; kawahara, Tetsushi	6/4/08	MS
USPAT USPGPUB EPO JPO DERWENT (EAST) see search printouts	6/4/08	MS
MEDLINE AGRICOLA BIOSIS CAPLUS EMBASE SCISEARCH (STN) see search printouts	6/4/08	MS
STIC sequence search, see SCORE	6/4/08	MS
updated inventor search in eDAN	2/19/09	MS
updated USPAT USPGPUB EPO JPO DERWENT (EAST) see search printout	2/19/09	MS

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

	/Michael Szperka/ Primary Examiner, Art Unit 1644
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